


<b>Search Notes</b>  	<b>Application/Control No.</b>  10520151	<b>Applicant(s)/Patent Under Reexamination</b>  KURITA, TADASHI
	<b>Examiner</b>  GELEK TOPGYAL	<b>Art Unit</b>  2621

SEARCHED			
Class	Subclass	Date	Examiner
386	46,65,66,95,98,102,109	3/13/2008	GT

SEARCH NOTES		
Search Notes	Date	Examiner
Thai Tran: Determined any subsampling system used for PIP processing meets the claimed invention.	3/13/2008	GT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner